

## Description

The NVTFS5826NLTWG uses advanced trench technology to provide excellent R<sub>DS(ON)</sub>, low gate

charge and operation with gate voltages as low as

4.5V. This device is suitable for use as a Battery

protection or in other Switching application.

#### **General Features**

V<sub>DS</sub> = 60V I<sub>D</sub> =40 A

 $R_{DS(ON)} < 15m\Omega$  @ V<sub>GS</sub>=10V

## Application

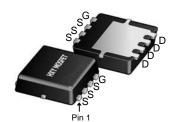
Battery protection

Load switch

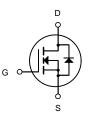
Uninterruptible power supply

## Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)		
NVTFS5826NLTWG	DFN3X3-8L	HXY MOSFET	5000		
Absolute Maximun	n Ratings (Tc=25℃unless	s otherwise noted)			
Symbol	Paramet	er	Rating	Units	
VDS	Drain-Source	Voltage	60	V	
VGS	Gate-Source Voltage		±20	V	
I⊳@Tc=25°C	Continuous Drain Curre	uous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>		А	
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>		20	А	
IDM	Pulsed Drain Current <sup>2</sup>		150	А	
EAS	Single Pulse Avalanche Energy <sup>3</sup>		36	mJ	
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>		30	W	
TSTG	Storage Temperat	Storage Temperature Range		°C	
TJ	Operating Junction Terr	perature Range	-55 to 150	°C	
R₀JA	Thermal Resistance Ju	nction-ambient <sup>1</sup>	62	°C/W	
R₀JC	Thermal Resistance J	lunction-Case <sup>1</sup>	2.5	°C/W	







N-Channel MOSFET



N-Channel Enhancement Mode MOSFET

#### Electrical Characteristics (TJ=25<sup>°</sup>C unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
Off Charac	cteristic		I	I	1	
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250µA	60	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V,	-	-	1.0	μA
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{DS}=0V$ , $V_{GS}=\pm 20V$	-	-	±100	nA
On Charac	cteristics					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	1.0	1.6	2.5	V
R <sub>DS(on)</sub>	Static Drain-Source on-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	12	15	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A	-	15	20	
Dynamic O	Characteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1.0MHz	-	930	-	pF
Coss	Output Capacitance		-	230	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	8	-	pF
Qg	Total Gate Charge	· V <sub>DS</sub> =30V, I <sub>D</sub> =20A, · V <sub>GS</sub> =10V	-	22	-	nC
$Q_gs$	Gate-Source Charge		-	4.5	-	nC
$Q_gd$	Gate-Drain("Miller") Charge	VGS-10V	-	3.5	-	nC
Switching	Characteristics					
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>DD</sub> =30V, I <sub>D</sub> =20A, R <sub>G</sub> =1.6Ω, V <sub>GS</sub> =10V	-	4.5	-	ns
tr	Turn-on Rise Time		-	2.7	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time		-	13.8	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	2.7	-	ns
Drain-Sou	rce Diode Characteristics and Maxim	um Ratings				
ls	Maximum Continuous Drain to Source Diode Forward Current		-	-	40	А
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	150	Α
$V_{\text{SD}}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =30A	-	-	1.2	V
t <sub>rr</sub>	Body Diode Reverse Recovery Time	TJ=25℃, I <sub>F</sub> =20A,dI/dt=100A/µs	-	18	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	12	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

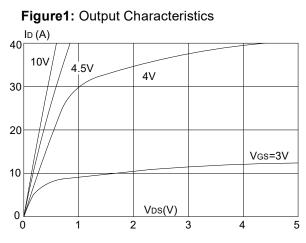
2. EAS condition: T\_J=25  $^\circ\! {\rm C}$  , V\_DD=30V, V\_G=10V, R\_G=25\Omega, L=0.5mH, I\_{AS}=12A

3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%

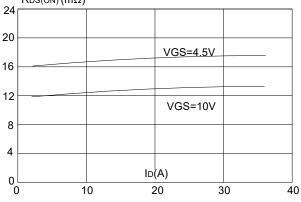


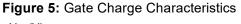
# NVTFS5826NLTWG N-Channel Enhancement Mode MOSFET

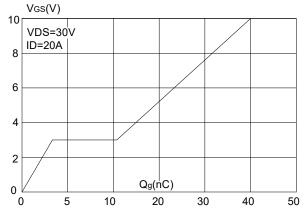
# **Typical Performance Characteristics**

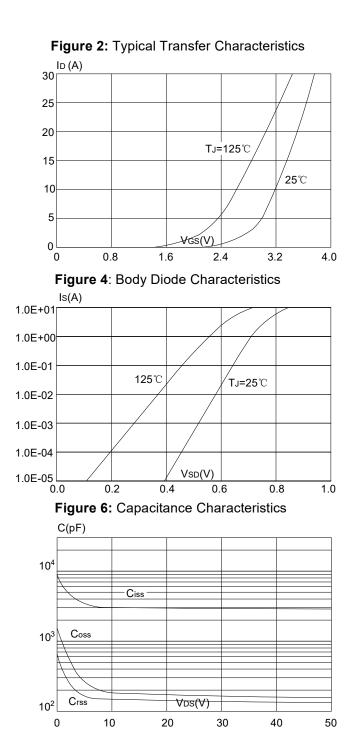


**Figure 3:**On-resistance vs. Drain Current RDS(ON) (mΩ)











**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature

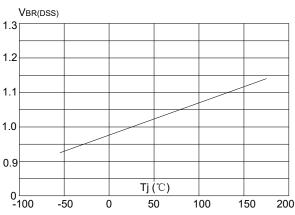
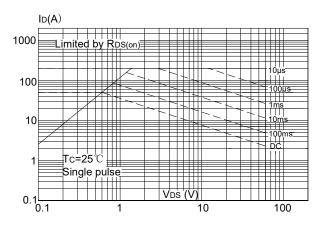
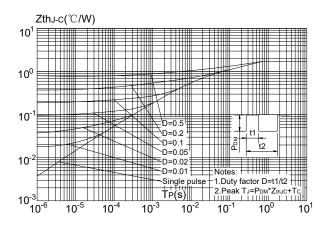


Figure 9: Maximum Safe Operating Area



**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



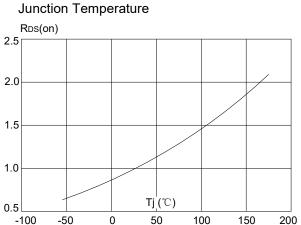


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

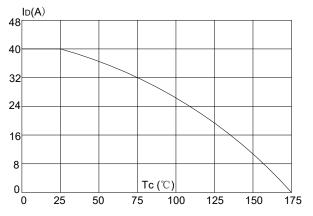
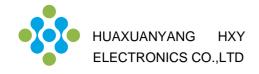
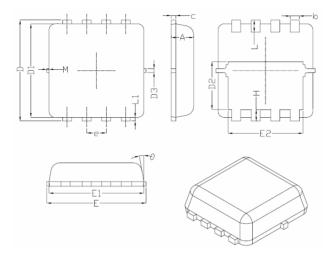


Figure 8: Normalized on Resistance vs.



# DFN3X3-8L Package Information



Strended	Dimensions In Millimeters			
Symbol	Min.	Nom.	Max.	
A	0.70	0.75	0.80	
b	0.25	0.30	0.35	
С	0.10	0.15	0.25	
D	3.25	3.35	3.45	
D1	3.00	3.10	3.20	
D2	1.48	1.58	1.68	
D3	-	0.13	-	
E	3.20	3.30	3.40	
E1	3.00	3.15	3.20	
E2	2.39	2.49	2.59	
e	0.65BSC			
Н	0.30	0.39	0.50	
L	0.30	0.40	0.50	
L1	-	0.13	-	
Μ	*	*	0.15	
θ		10 <sup>°</sup>	12 <sup>°</sup>	



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